



## Product/Process Change Notice - PCN 07\_0090 Rev. A

Analog Devices, Inc. Three Technology Way Norwood, Massachusetts 02062-9106

This notice is to inform you of a change that will be made to certain ADI products (see Material Report). Any issues with this PCN or requirements to qualify the change (additional data or samples) must be sent to ADI within 30 days of publication date. ADI contact information is listed below.

Note: Revised fields are indicated by a red field name. See Appendix B for revision history.

**PCN Title:** Certification of STATSChipPAC China (SCC) as an additional Test facility for ADI

**Publication Date:** 13-Jan-2010

**Effectivity Date:** 13-Jan-2010 (the earliest date that a customer could expect to receive changed material)

### Revision Description:

Revise PCN to clarify strategy as using SCC as an additional test source for affected parts. Either facility may be used to test these parts in order to meet customer demand.

### Description Of Change

ADI is certifying STATSChipPAC China(SCC)as an additional Test facility for ADI.

#### Test flow

ADI will be certifying SCC for Test of selected SSOP/SOIC/LFCSP package body sizes.

ADI will be certifying SCC for Test on select products presently tested at ADI's Philippine Test Facility (ADGT).

Nine (9) generics from three (3) package types will initially be qualified and transferred. Additional products will be qualified and transferred depending on volume and capacity requirements. Parts list is provided with this PCN.

#### Details:

Device quality, function, and performance, as specified by Product Data Sheets, will be unaffected by this change.

There is no change on the Form, Fit and Function of the products being transferred from ADGT.

ADGT Test Manufacturing equipment will be transferred to SCC for the initial production ramp.

ADI specified Manufacturing Process instructions will be used at SCC.

ADI Engineers will be on-site at SCC providing support for Test.

SCC and ADGT may be concurrent or interchangeable test sites for ADI products.

### Reason For Change

Analog Devices will be certifying SCC as an additional Test facility for ADI products. Analog Devices is committed to ensuring the necessary manufacturing capability and capacity exists to meet our customers' volume requirements. This certification is in line with Analog Devices' strategy to establish additional Test manufacturing capability and capacity to react to sudden upswings in test volume.

Moreover, ADI may test at either or both test sites to satisfy volume requirements.

### Impact of the change (positive or negative) on fit, form, function & reliability

There is no change to the form, fit, function, quality or reliability of the transferred parts.

### Summary of Supporting Information

Qualification will be performed per Analog Devices specification ADI0012, Procedure for Qualification of New or Revised Processor Products. A Report will be available upon request after completion of the qualification.

Any special requests should be identified within the first 30 days of this PCN.

### Supporting Documents

**Attachment 1: Type:** Detailed Parts List

ADI\_PCN\_07\_0090\_Rev\_A\_07\_0090\_PL.xls

For questions on this PCN, send email to the regional contacts below or contact your local ADI sales representative

**Americas:** PCN\_Americas@analog.com

**Europe:** PCN\_Europe@analog.com

**Japan:** PCN\_Japan@analog.com

**Rest of Asia:** PCN\_ROA@analog.com



**Appendix A - Affected ADI Models**

**Existing Parts - Product Family / Model Number (76)**

ADE7753 / AD71045ARS	ADE7753 / ADE7753ARS	ADE7753 / ADE7753ARSRL	ADE7753 / ADE7753ARSZ	ADE7753 / ADE7753ARSZRL	ADE7755 / AD71057ARS
ADE7755 / AD71057ARSRL	ADE7755 / AD71057ARSZ	ADE7755 / AD71057ARSZ-RL	ADE7755 / AD71079ARS	ADE7755 / AD71079ARSRL	ADE7755 / ADE7755ARS
ADE7755 / ADE7755ARSRL	ADE7755 / ADE7755ARSZ	ADE7755 / ADE7755ARSZRL	ADE7759 / AD71039ARS	ADE7759 / AD71039ARSRL	ADE7759 / AD71039ARSZ
ADE7759 / AD71039ARSZRL	ADE7759 / ADE7759ARS	ADE7759 / ADE7759ARSRL	ADE7759 / ADE7759ARSZ	ADE7759 / ADE7759ARSZRL	ADE7761A / ADE7761AARS
ADE7761A / ADE7761AARS-RL	ADE7761A / ADE7761AARSZ	ADE7761A / ADE7761AARSZ-RL	ADE7761B / ADE7761BARS	ADE7761B / ADE7761BARS-RL	ADE7761B / ADE7761BARSZ
ADE7761B / ADE7761BXRS	ADE7761B / ADE7761BXRSZ	ADM1485 / AD51/062-0	ADM1485 / AD51/062-0REEL	ADM1485 / AD51/062Z-0REEL	ADM1485 / ADM1485AR
ADM1485 / ADM1485AR-REEL	ADM1485 / ADM1485AR-REEL7	ADM1485 / ADM1485ARZ	ADM1485 / ADM1485ARZ-REEL	ADM1485 / ADM1485ARZ-REEL7	ADM1485 / ADM1485JR
ADM1485 / ADM1485JR-REEL	ADM1485 / ADM1485JR-REEL7	ADM1485 / ADM1485JRZ	ADM1485 / ADM1485JRZ-REEL	ADM1485 / ADM1485JRZ-REEL7	ADM485 / AD51/025-1
ADM485 / AD51/025-1REEL	ADM485 / AD51/025Z-1	ADM485 / AD51/025Z-1REEL	ADM485 / AD51/060-0	ADM485 / AD51/060-0REEL	ADM485 / AD51/060Z-0REEL
ADM485 / AD51/061-0	ADM485 / AD51/061-0REEL	ADM485 / AD51/061-0REEL7	ADM485 / ADM485AR	ADM485 / ADM485AR-REEL	ADM485 / ADM485ARZ
ADM485 / ADM485ARZ-REEL	ADM485 / ADM485JR	ADM485 / ADM485JR-REEL	ADM485 / ADM485JR-REEL7	ADM485 / ADM485JRZ	ADM485 / ADM485JRZ-REEL
ADM485 / ADM485JRZ-REEL7	ADXL321 / ADXL321JCP	ADXL321 / ADXL321JCP-REEL	ADXL321 / ADXL321JCP-REEL7	ADXL323 / ADXL323KCPZ	ADXL323 / ADXL323KCPZ-RL
ADXL323 / ADXL323KCPZ-RL7	ADXL330 / ADXL330KCPZ	ADXL330 / ADXL330KCPZ-RL	ADXL330 / ADXL330KCPZ-RL7		

**Appendix B - Revision History**

<b>Rev</b>	<b>Publish Date</b>	<b>Rev Description</b>
Rev. -	20-Nov-2007	Initial Release
Rev. A	13-Jan-2010	Revise PCN to clarify strategy as using SCC as an additional test source for affected parts. Either facility may be used to test these parts in order to meet customer demand.

Analog Devices, Inc.

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